

(19)



(11)

EP 2 190 002 B8

(12)

CORRECTED EUROPEAN PATENT SPECIFICATION

(15) Correction information:

Corrected version no 1 (W1 B1)
Corrections, see
Bibliography INID code(s) 73

(51) Int Cl.:

H01J 37/244 ^(2006.01) **H01J 37/28** ^(2006.01)
H01J 37/285 ^(2006.01)

(48) Corrigendum issued on:

14.09.2016 Bulletin 2016/37

(45) Date of publication and mention of the grant of the patent:

01.06.2016 Bulletin 2016/22

(21) Application number: **10001779.7**

(22) Date of filing: **10.09.2002**

(54) **Method for detecting a fine geometry**

Verfahren zur Erfassung einer feinen Geometrie

Procédé de détection d'une géométrie fine

(84) Designated Contracting States:

DE FR GB NL

(30) Priority: **10.09.2001 JP 2001273432**

(43) Date of publication of application:

26.05.2010 Bulletin 2010/21

(60) Divisional application:

16172147.7

(62) Document number(s) of the earlier application(s) in accordance with Art. 76 EPC:

02020243.8 / 1 291 900

(73) Proprietor: **EBARA CORPORATION**

**Ohta-ku,
Tokyo (JP)**

(72) Inventors:

- **Hatakeyama, Masahiro**
Ohta-ku, Tokyo (JP)
- **Murakami, Takeshi**
Tokyo (JP)
- **Satake, Tohru**
Kanagawa-ken (JP)

- **Noji, Nobuharu**
Kanagawa-ken (JP)
- **Nagahama, Ichirota**
Ibaraki-ken (JP)
- **Yamazaki, Yuichiro**
Tokyo (JP)

(74) Representative: **Carstens, Dirk Wilhelm**

Wagner & Geyer
Gewürzmühlstraße 5
80538 München (DE)

(56) References cited:

EP-A2- 0 590 308 JP-A- 2000 215 841
US-A- 5 004 919 US-B1- 6 184 526

- **HORACEK MIROSLAV: "Detection of the angular distribution of the signal electrons in VLESEM" JOURNAL OF COMPUTER-ASSISTED MICROSCOPY, PLENUM PRESS, NEW YORK, NY, US, vol. 10, no. 1, 1 January 1999 (1999-01-01), pages 23-32, XP009098872 ISSN: 1040-7286**

Note: Within nine months of the publication of the mention of the grant of the European patent in the European Patent Bulletin, any person may give notice to the European Patent Office of opposition to that patent, in accordance with the Implementing Regulations. Notice of opposition shall not be deemed to have been filed until the opposition fee has been paid. (Art. 99(1) European Patent Convention).

EP 2 190 002 B8

- **TAHER DAUD ET AL: "Charge -coupled-device response to electron beam energies of less than 1 keV up to 20 keV", OPTICAL ENGINEERING., vol. 26, no. 8, 1 August 1987 (1987-08-01) , pages 686-691, XP055166671, BELLINGHAM ISSN: 0091-3286**